

SPIROC measurements status and **proposal for SiPM readout**

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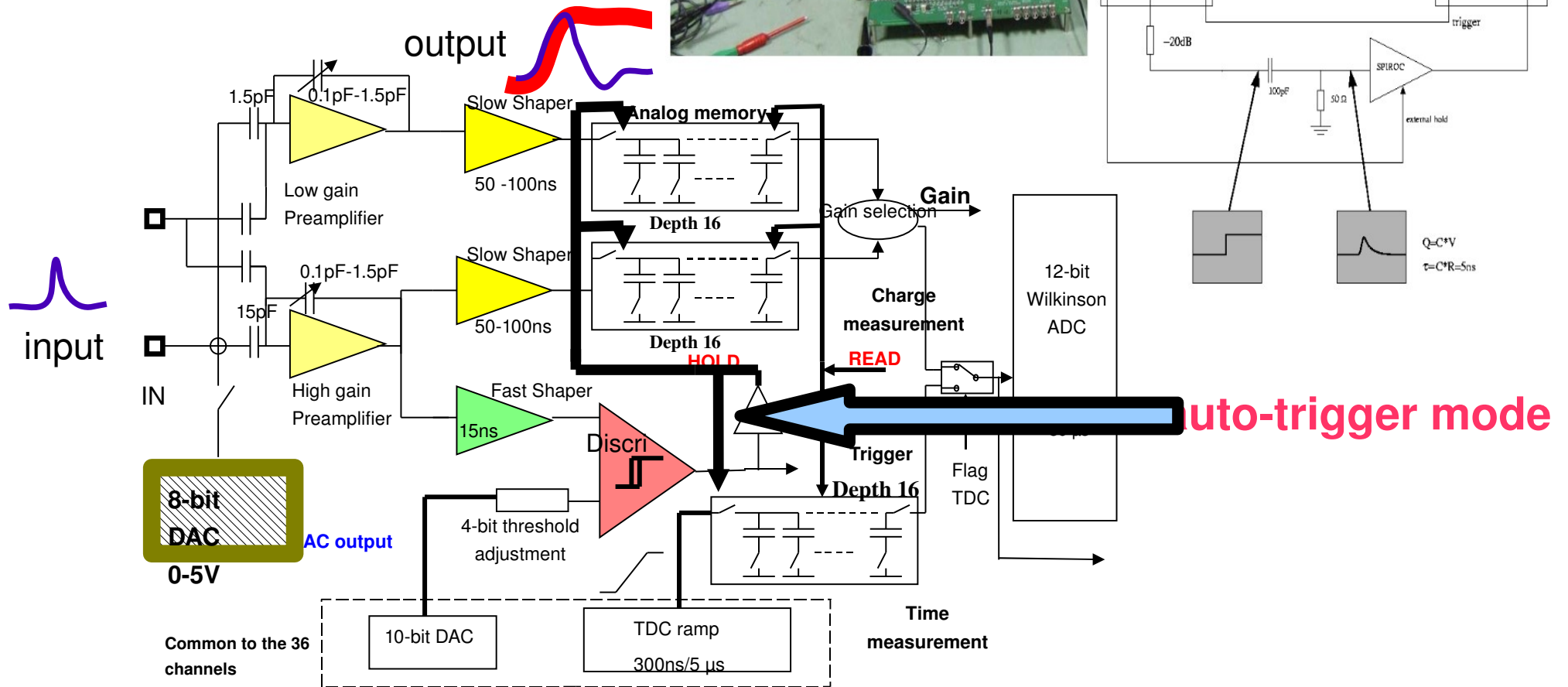
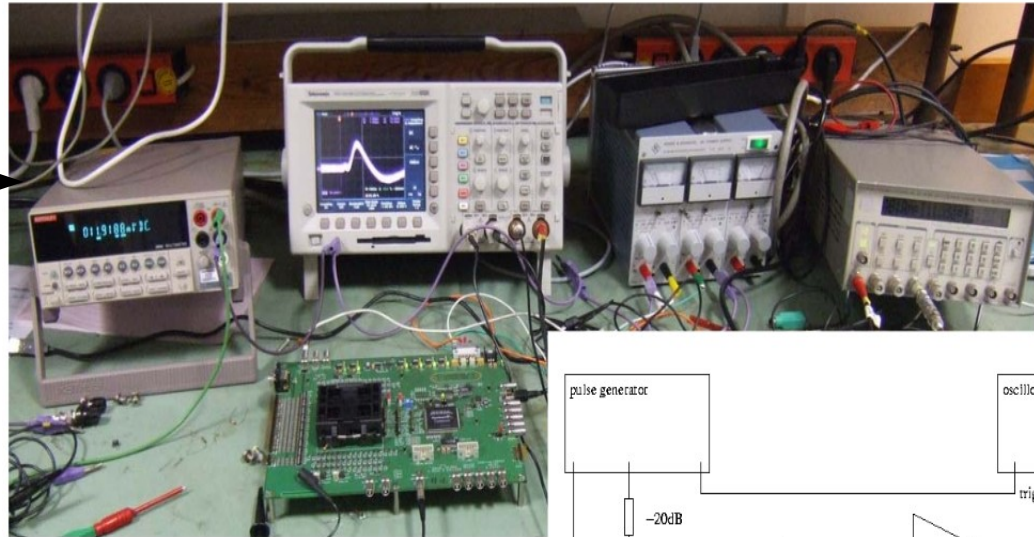
Riccardo Fabbri (DESY)

Benjamin Lutz (DESY)

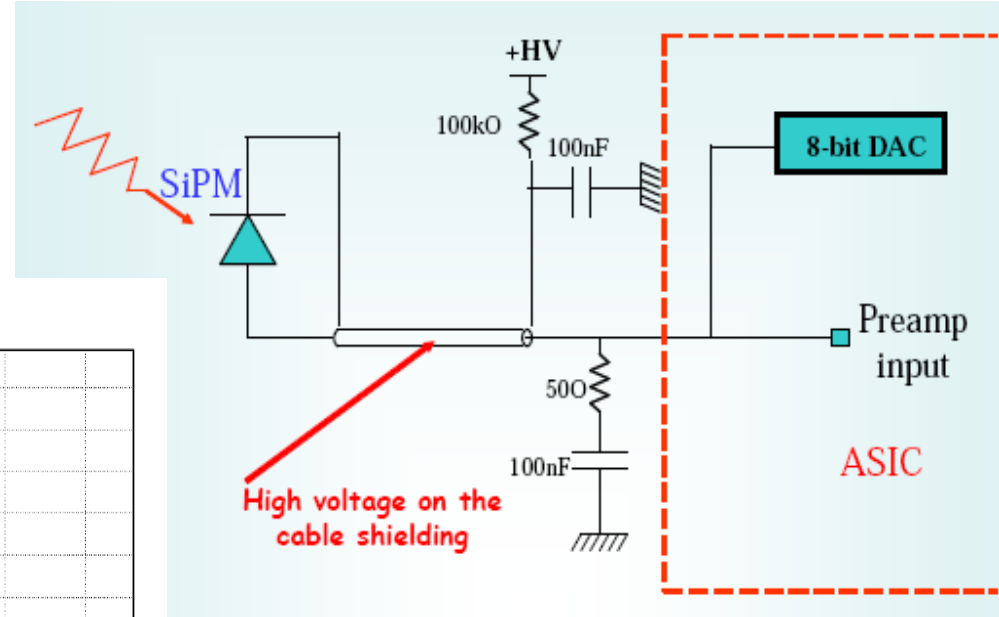
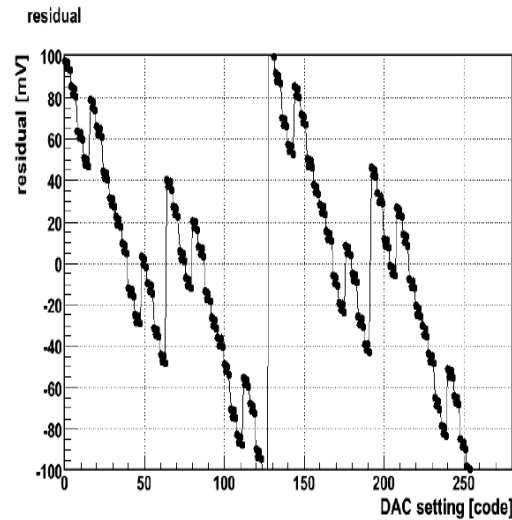
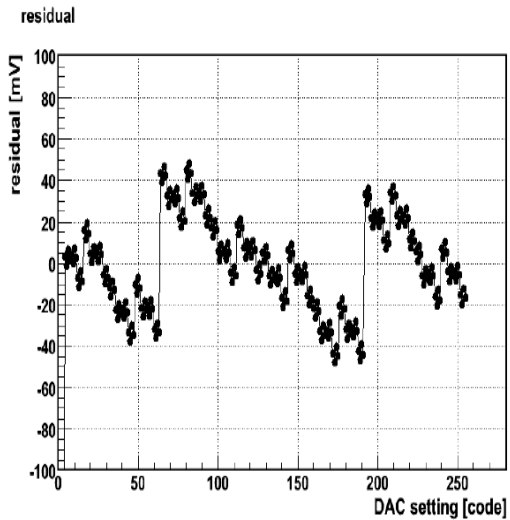
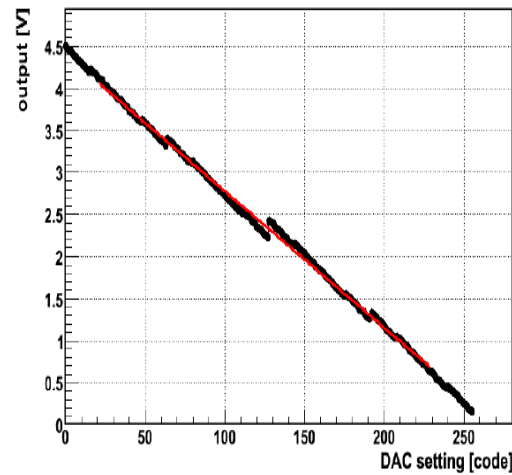
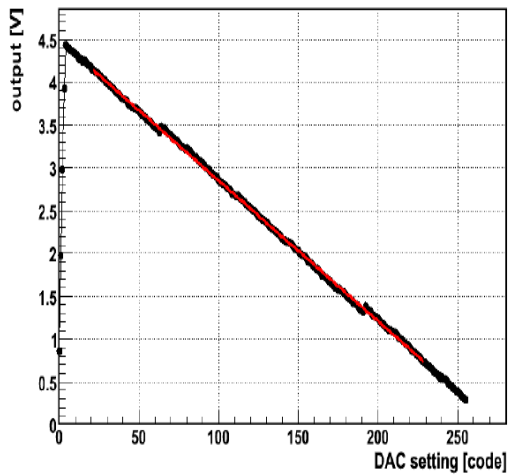
status of measurements – analog part

Test setup:

Pulser + Coupling C + Oscilloscope



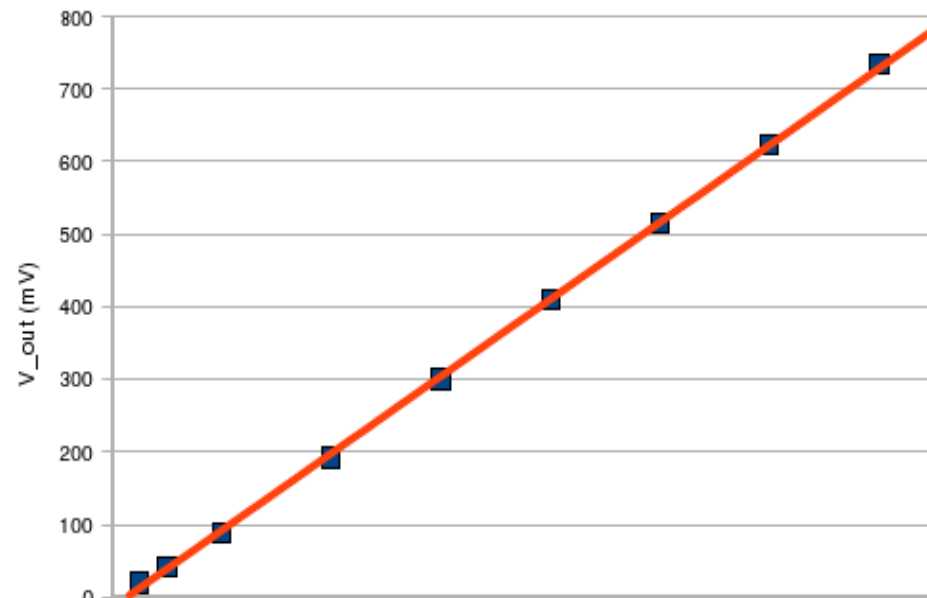
Input DAC



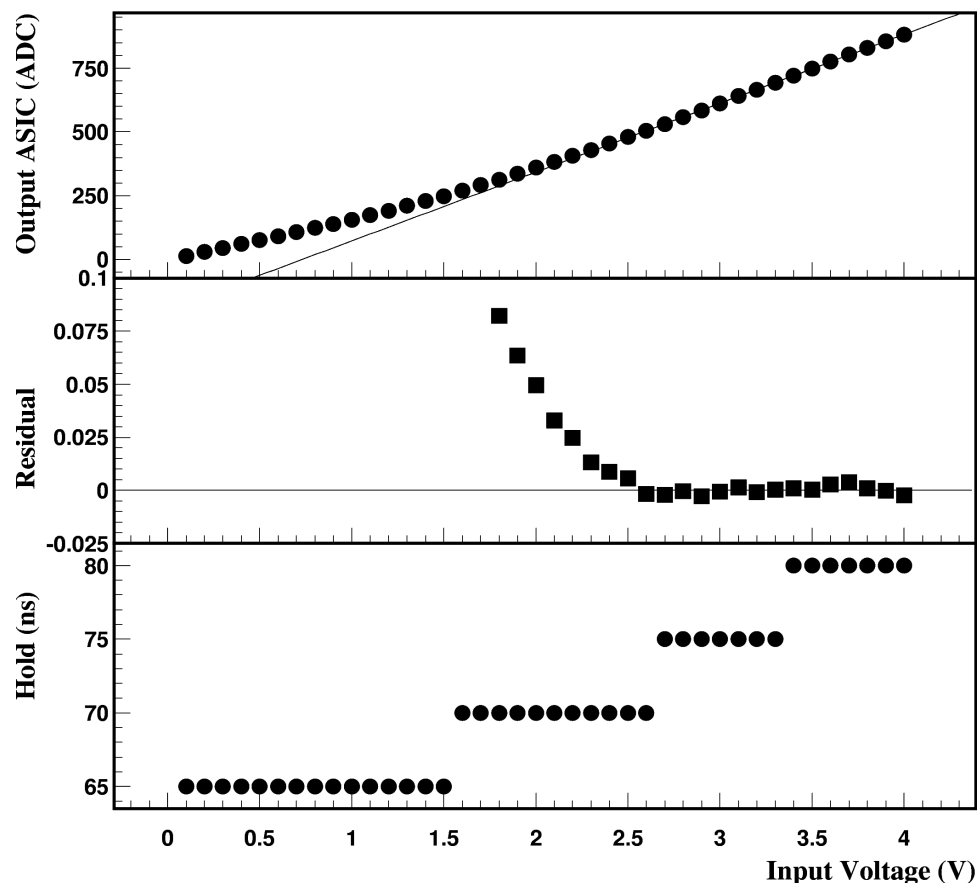
- swing 4.5V
- tune SiPM voltage
- residual $\pm 2\%$
- consistent with Orsay measurements

linearity and peaking time

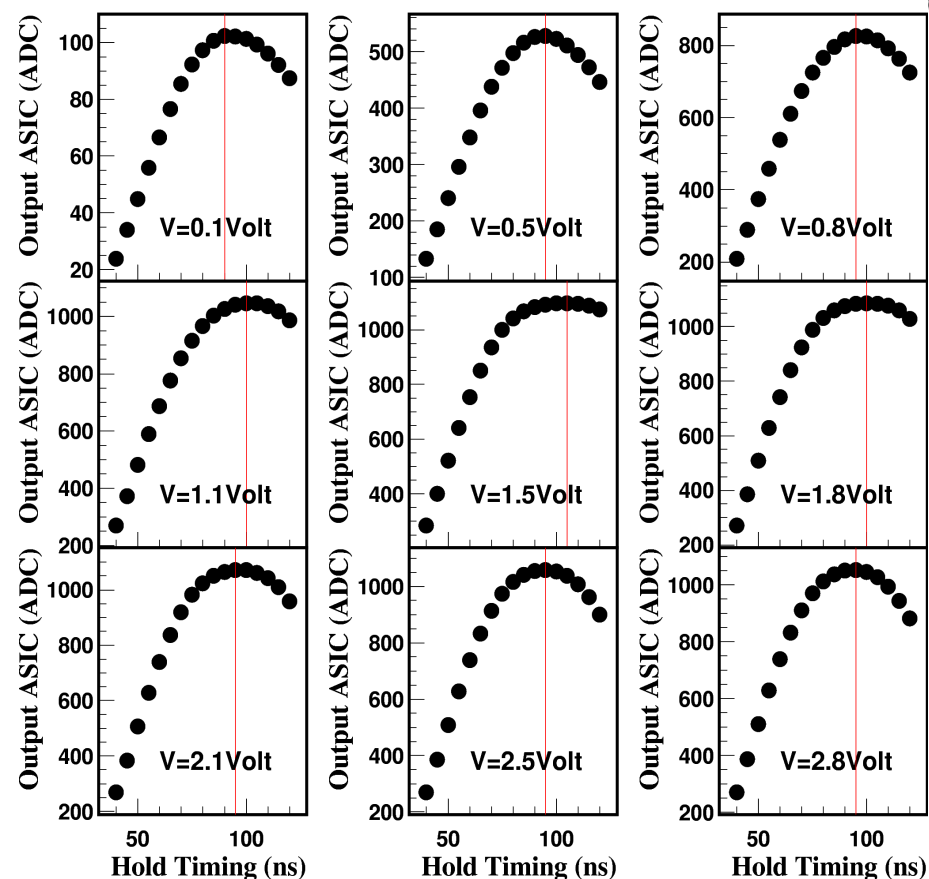
$C_f = 700\text{fF}$, $\tau = 50\text{ns}$, $C_c = 100\text{pF}$, 20dB



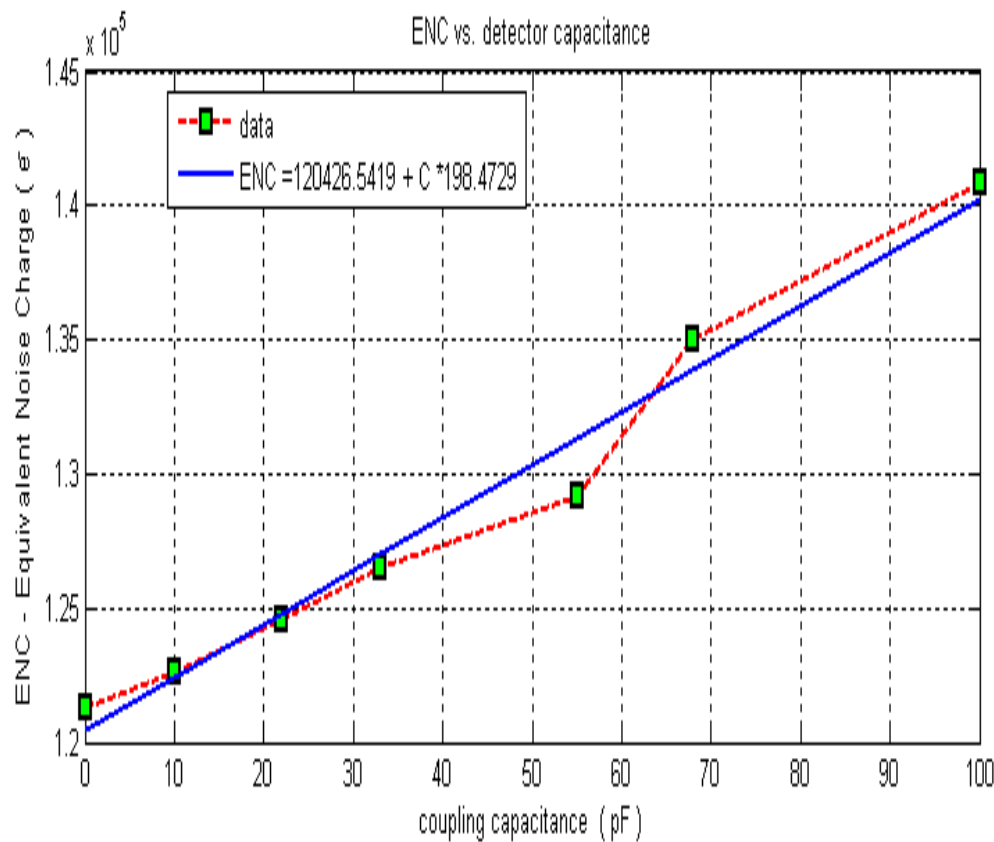
HG mode: Variable Capacitance: 1500fF Shaping Time: 50ns



HG mode: Variable Capacitance: 100fF Shaping Time: 50ns

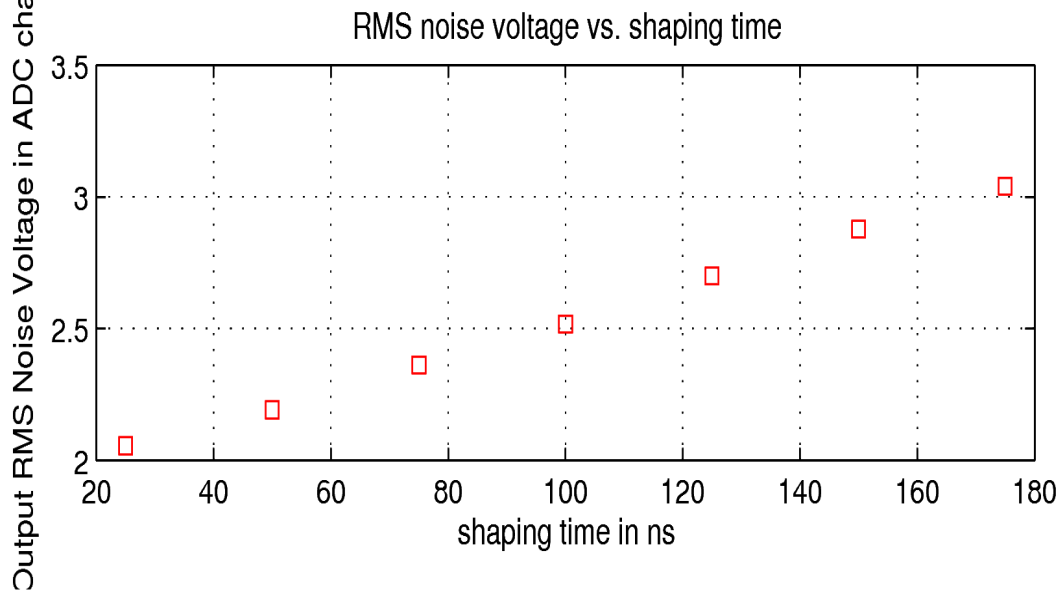
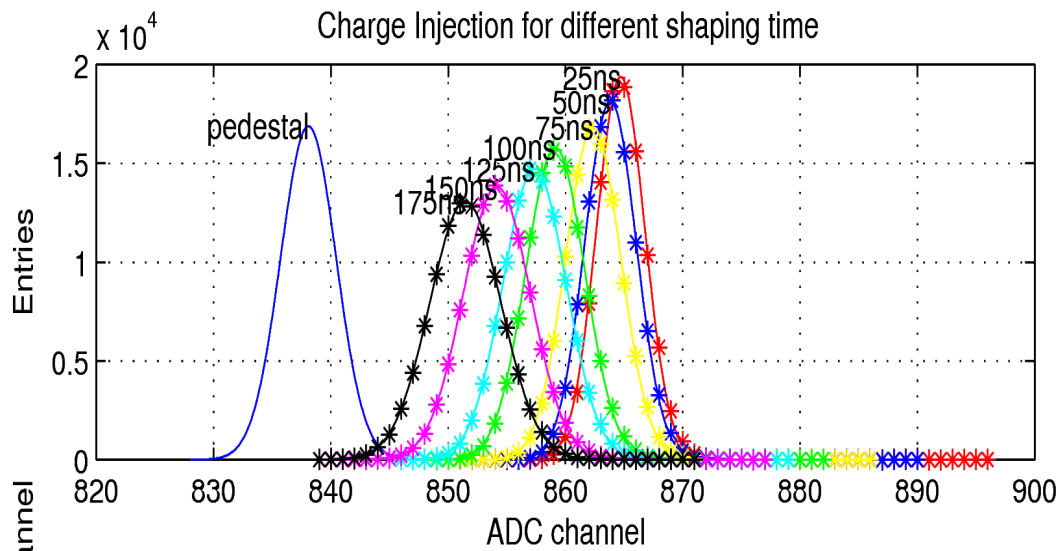


equivalent noise charge vs. detector capacitance



1.3×10^5 electrons @
SiPM cap. ~ 50 pF

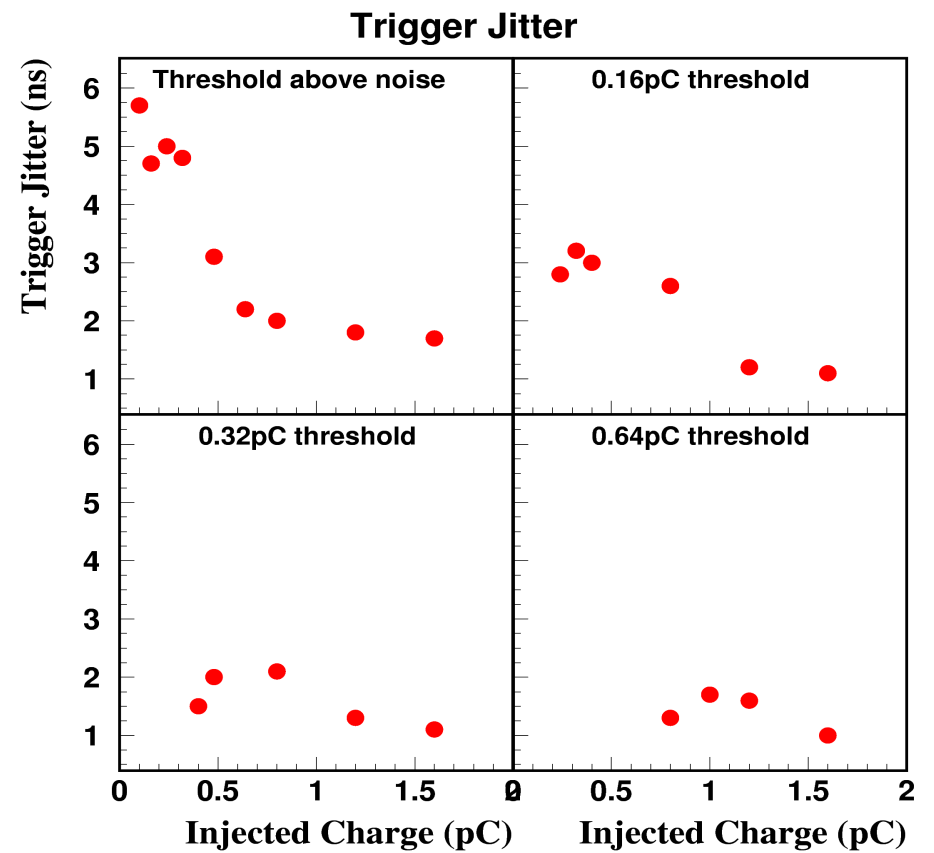
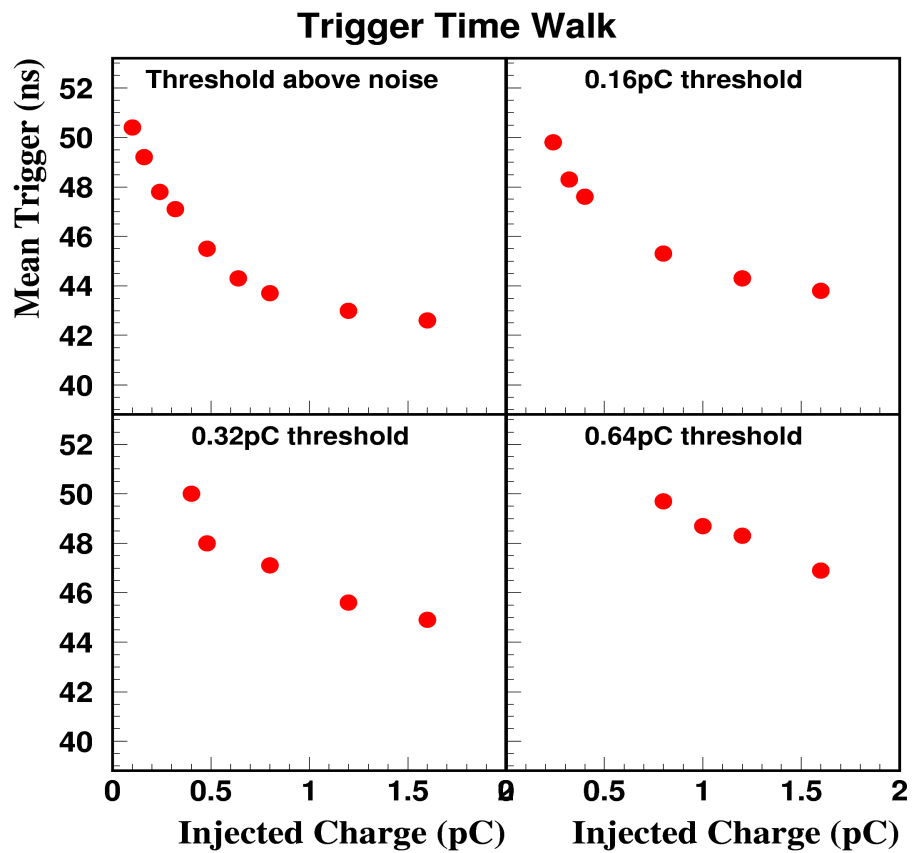
Sg/N ~ 3.8 @
SiPM Gain 0.5×10^6



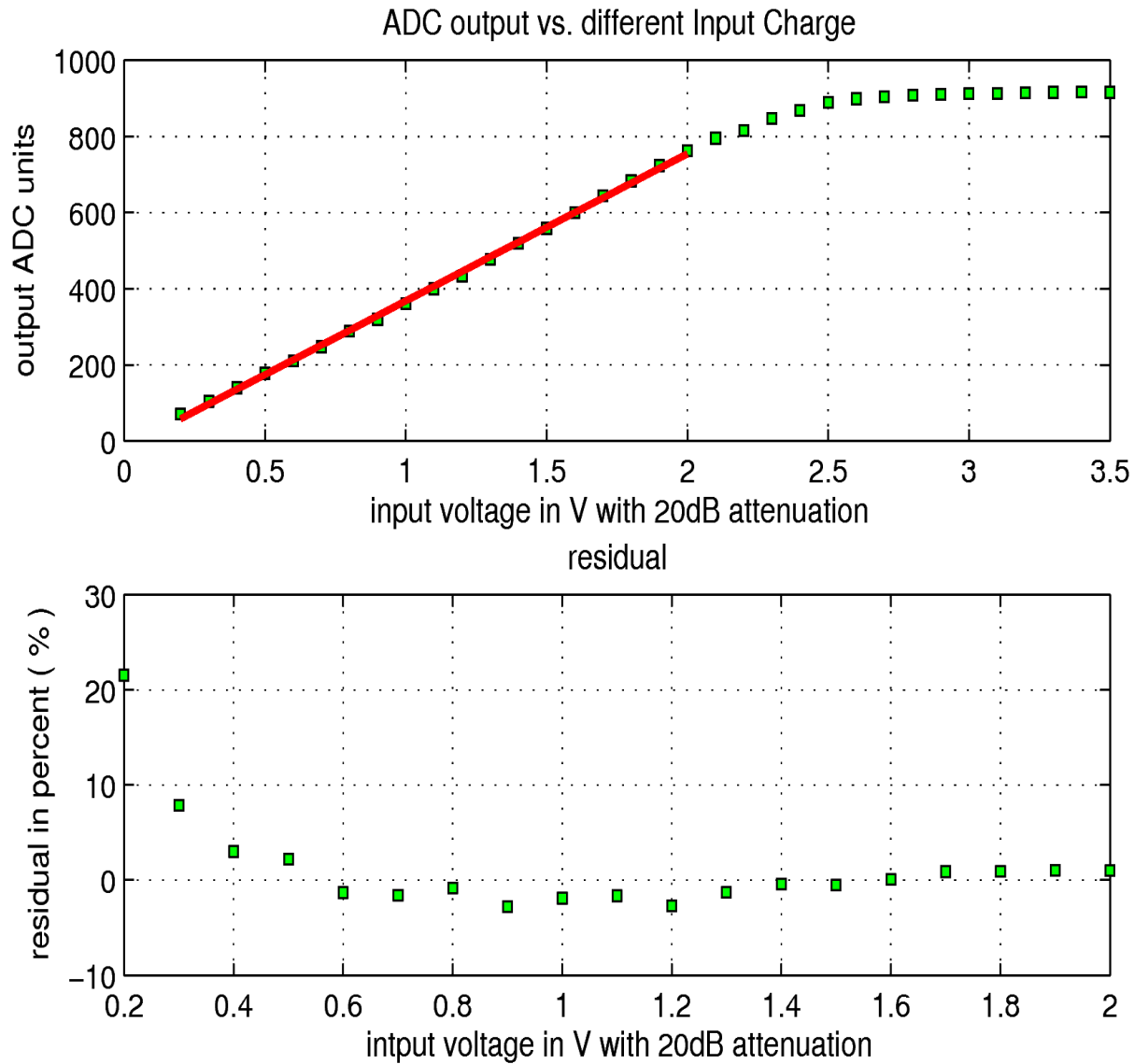
noise increase
with shaping time

low frequency noise

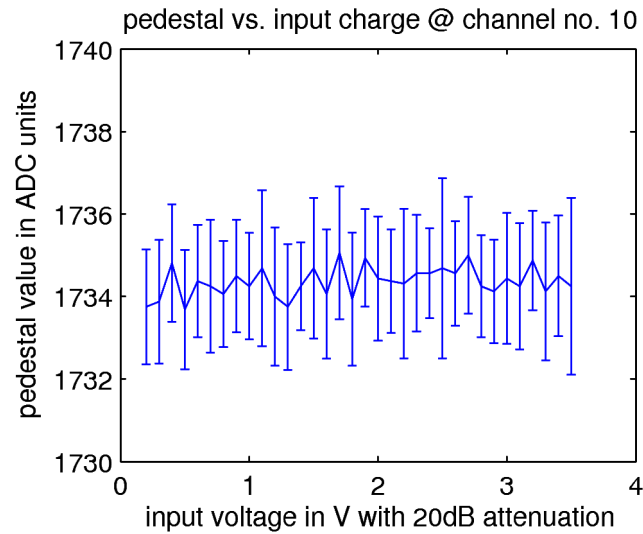
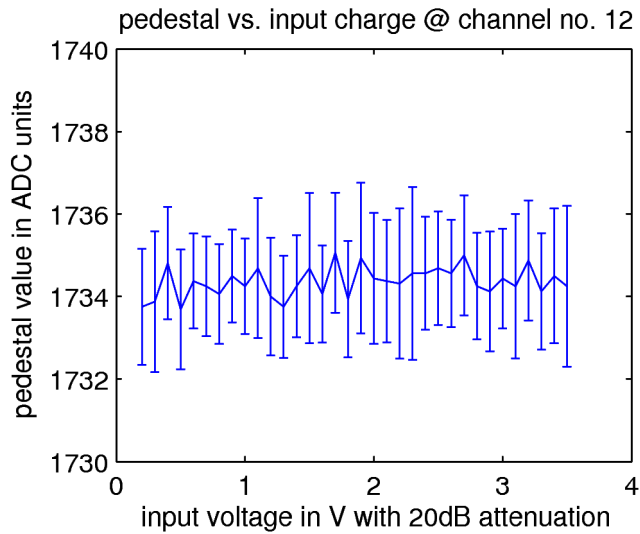
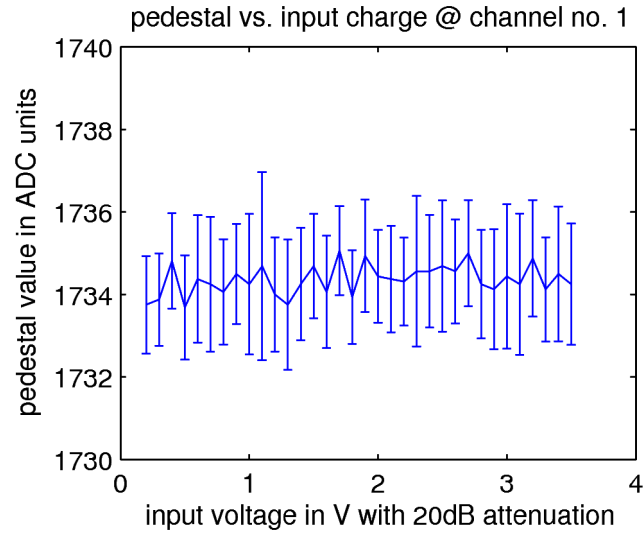
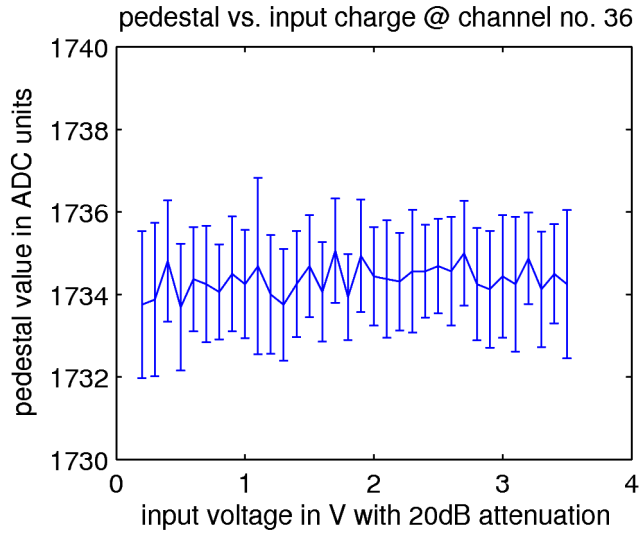
time walk and jitter



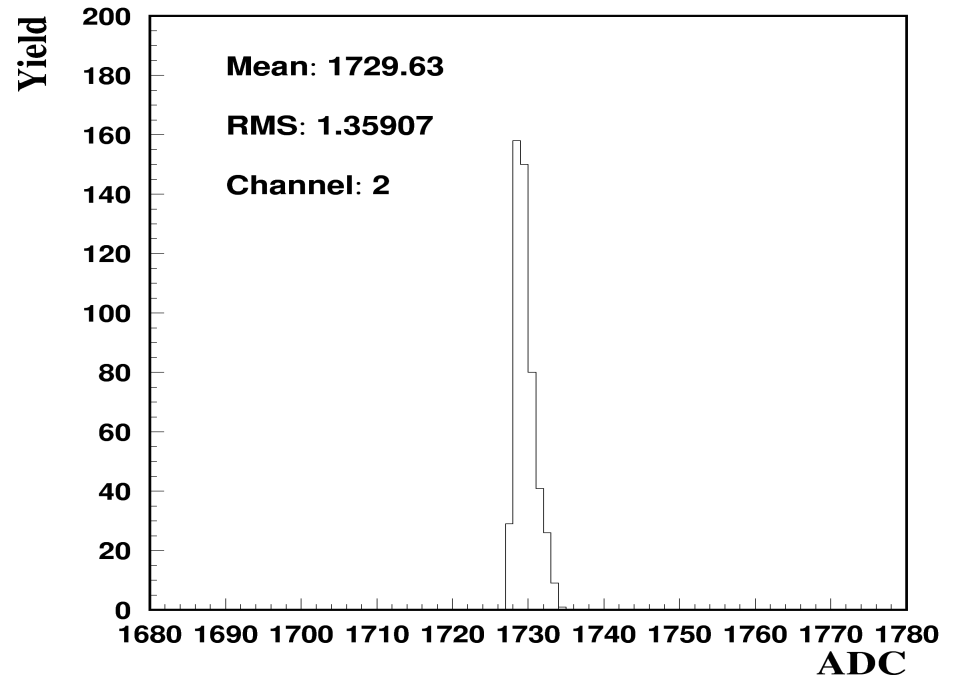
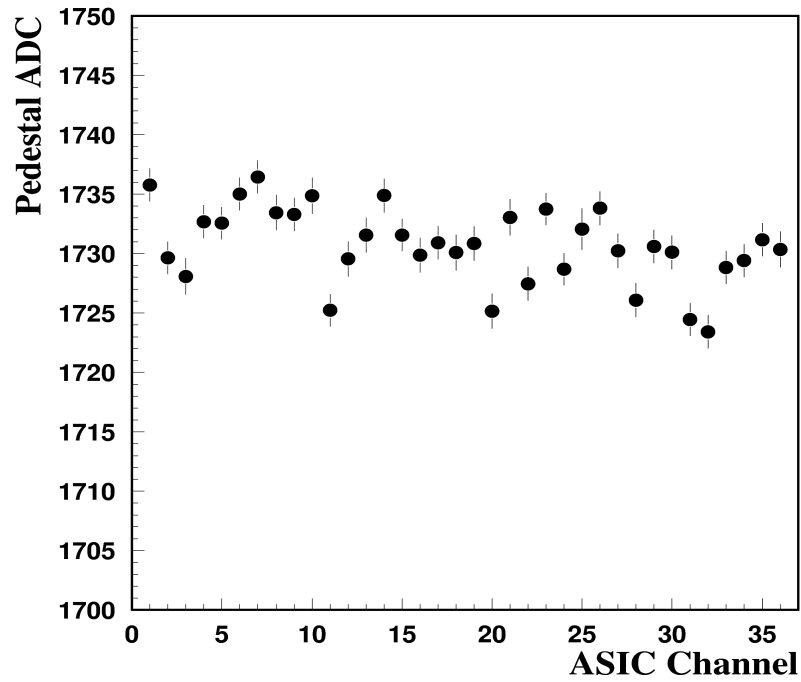
Wilkinson ADC testing



pedestal uniformity

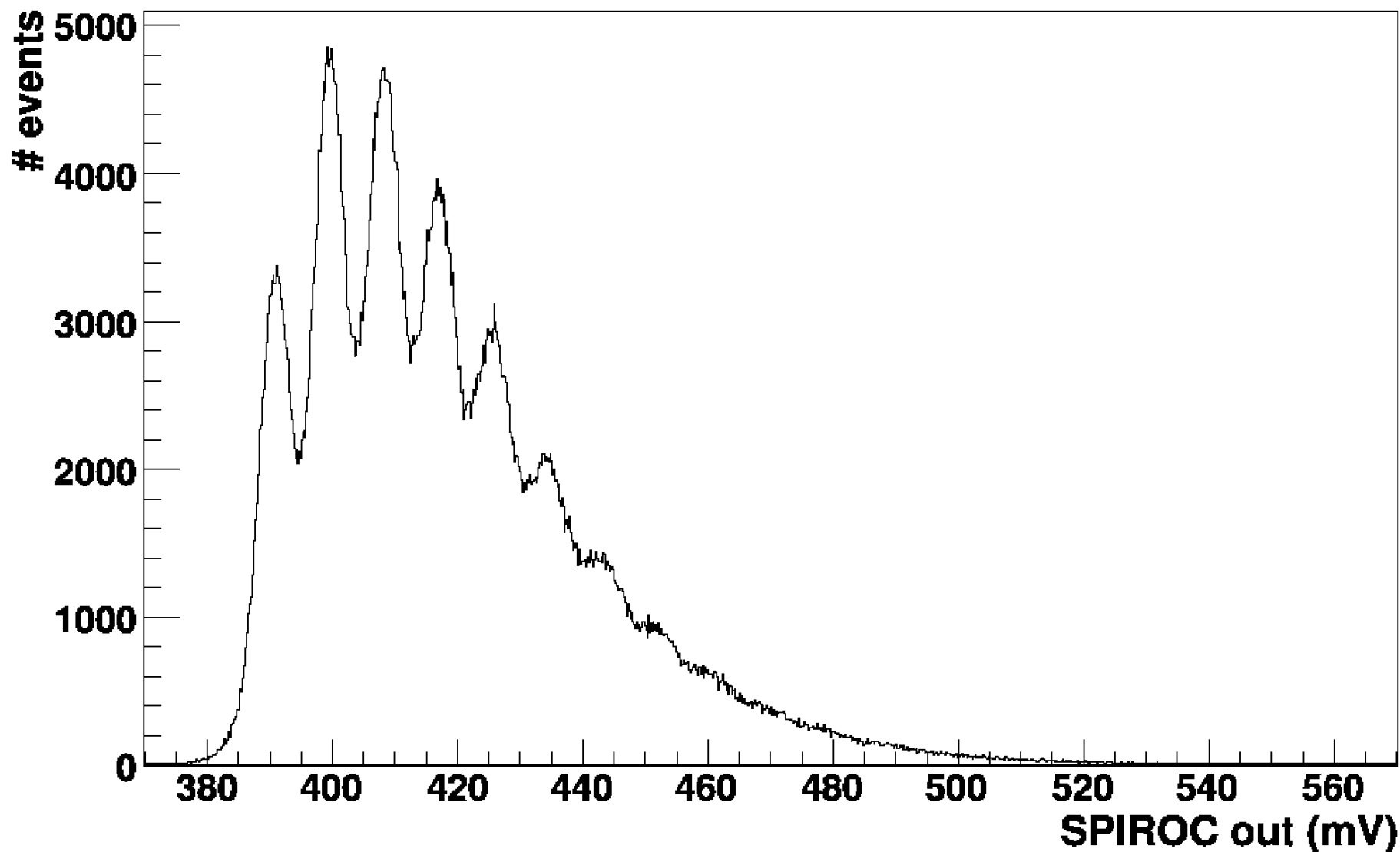


pedestal distributions of all the channels

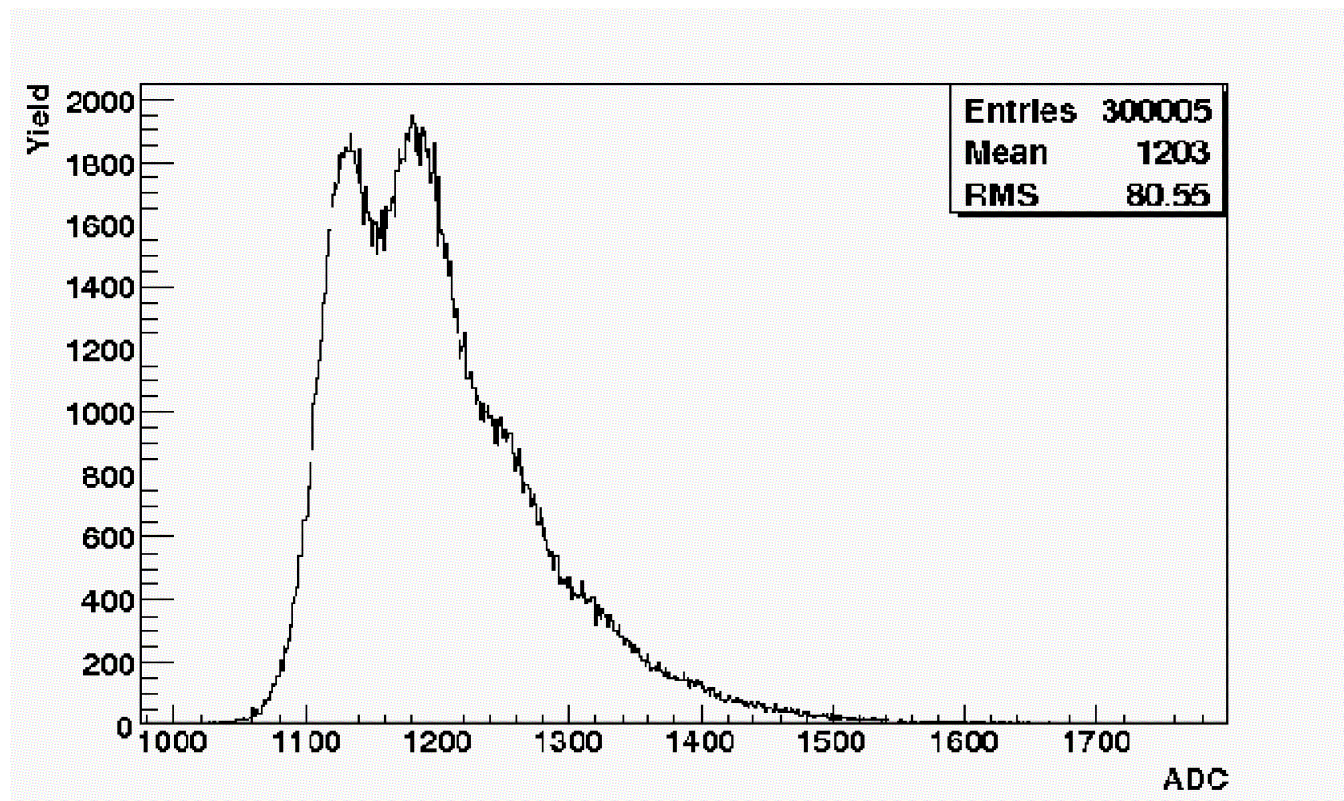


RMS ~ 3.09 ADC

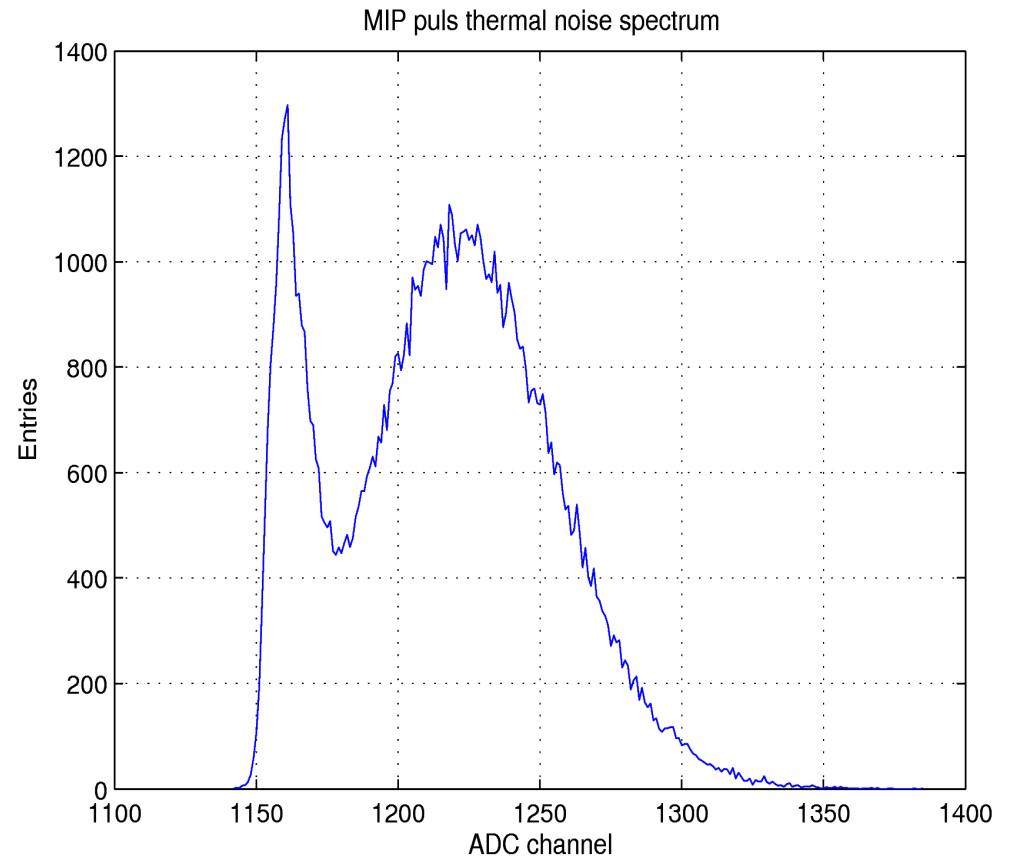
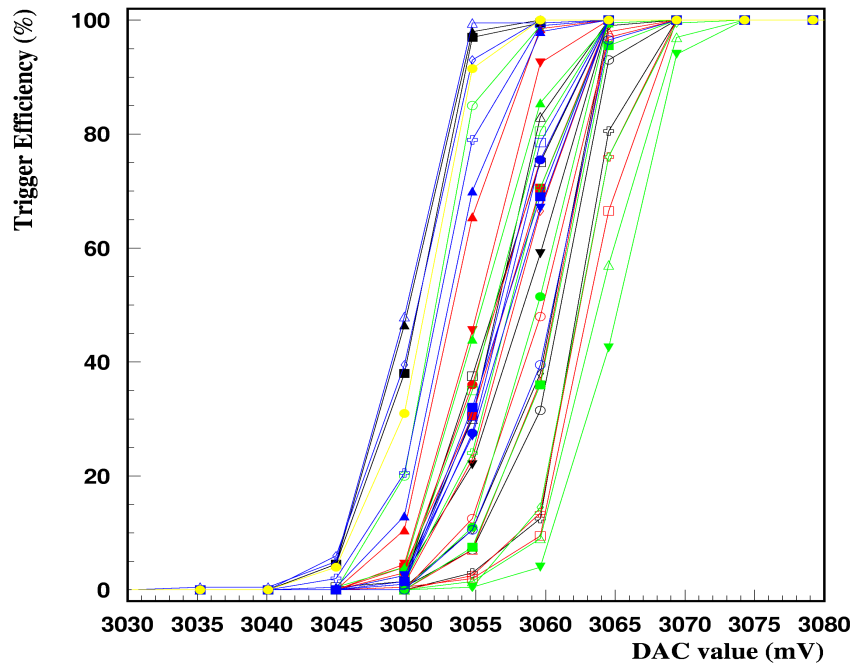
SiPM 753 SPIROC HG 100fF 50ns external hold



thermal noise spectrum



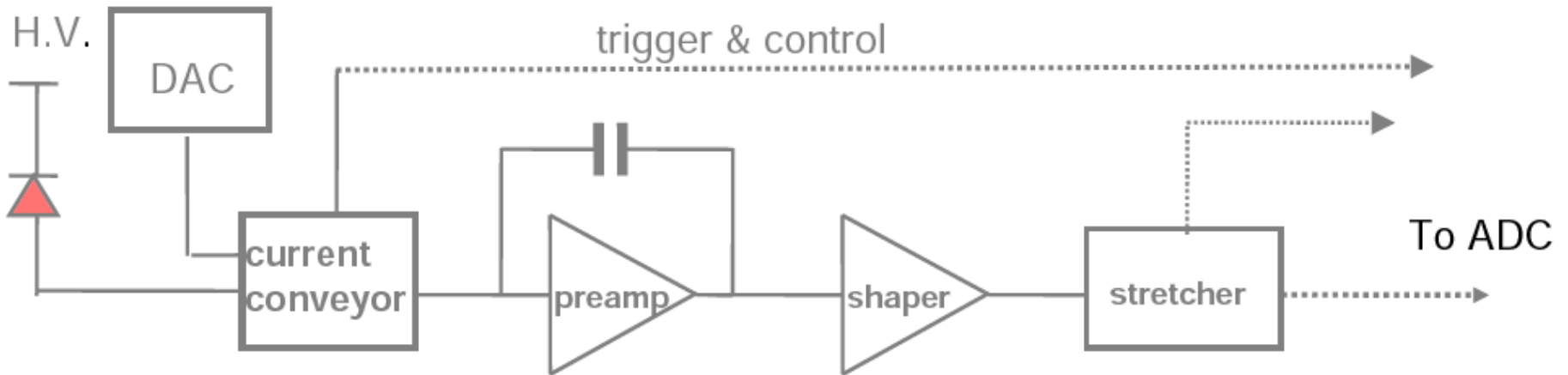
S-Curve and thermal noise + MIP signal



outlook

1. internal delay -> spectrum
2. TAC : resolution , input signal synchronization
3. power pulsing
4. multi-channel test

single channel architecture



input DAC : gain tuning

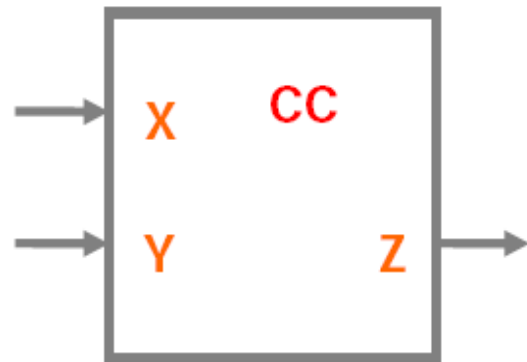
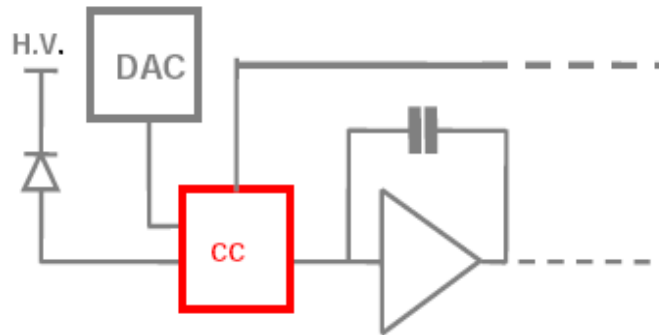
current conveyor : fast rising edge and large dynamic range

CSA : high signal to noise ratio

different shaping time : avoid pile up

AMS 0.35um CMOS technology

current conveyer



$$V_Y = V_X \quad I_Z = I_Y \quad I_X = 0$$

DAC disconnected to signal line

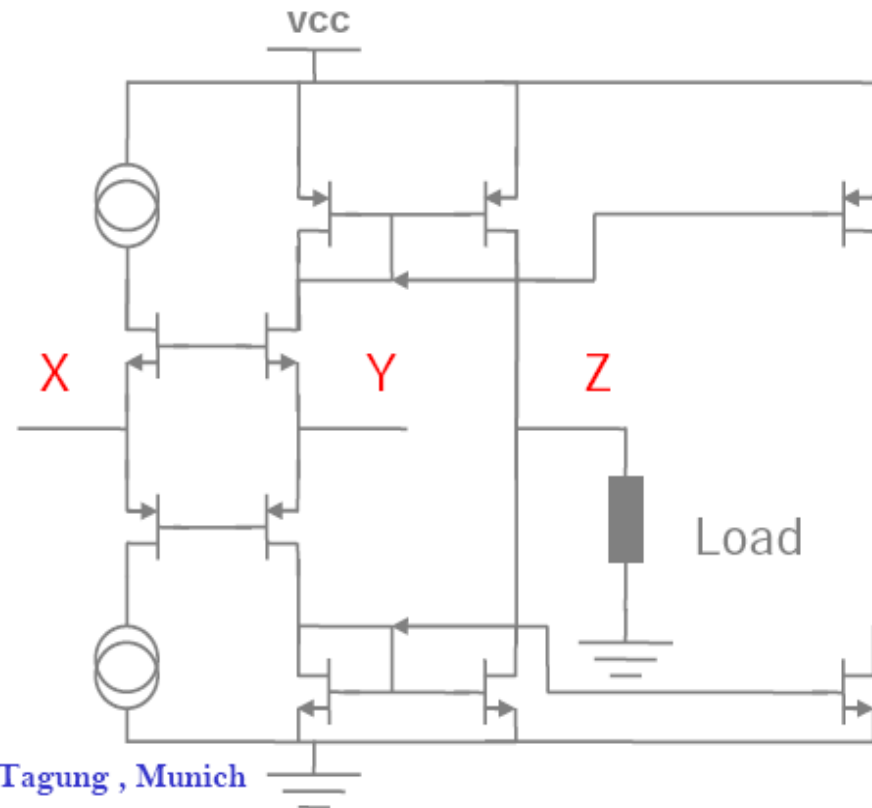
→ avoid disturbance

input impedance tunable $\sim 1/g_m$

→ fast timing

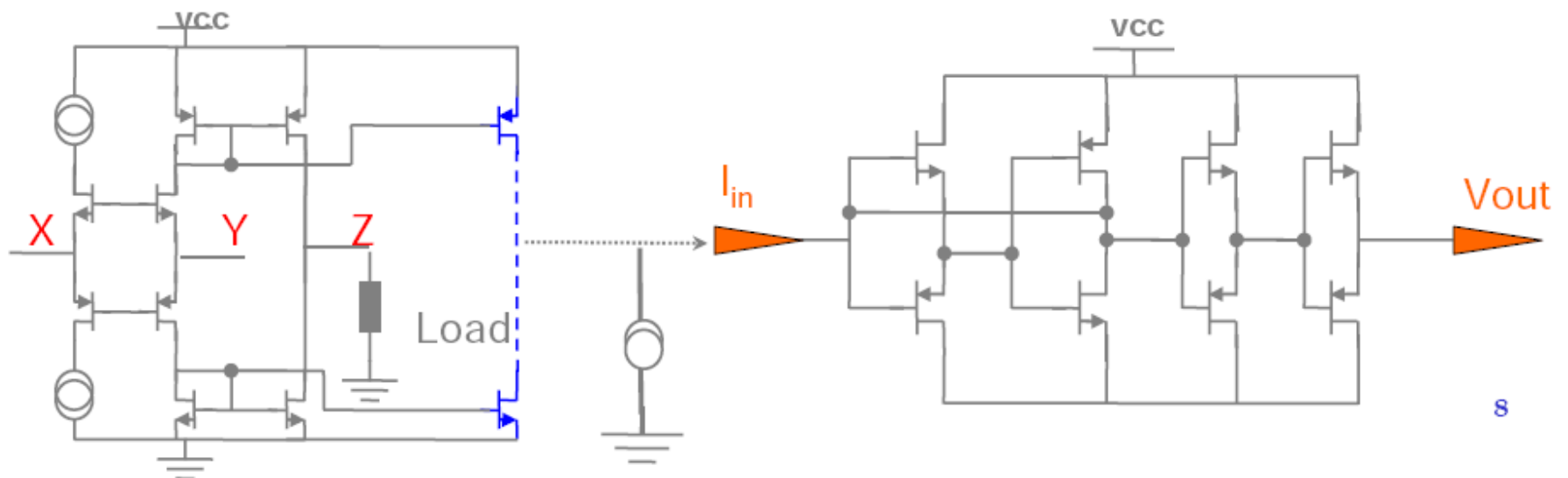
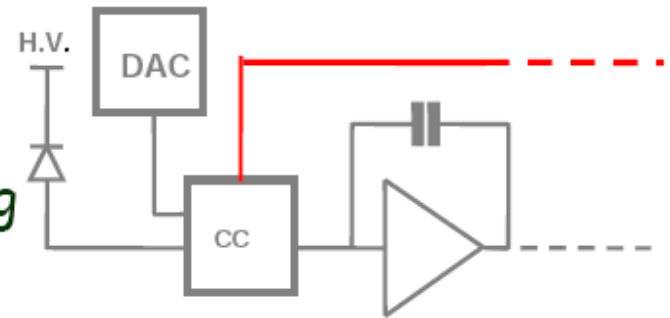
mirror for fast triggering

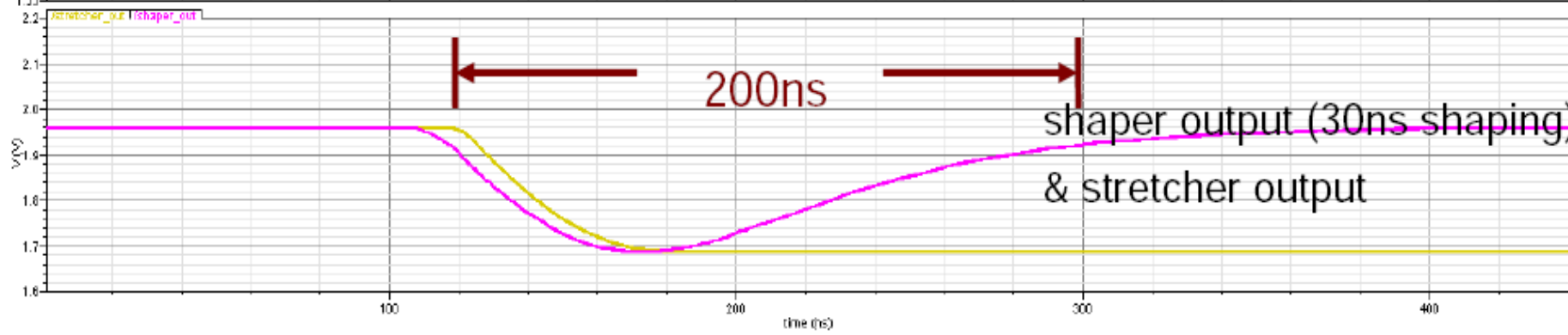
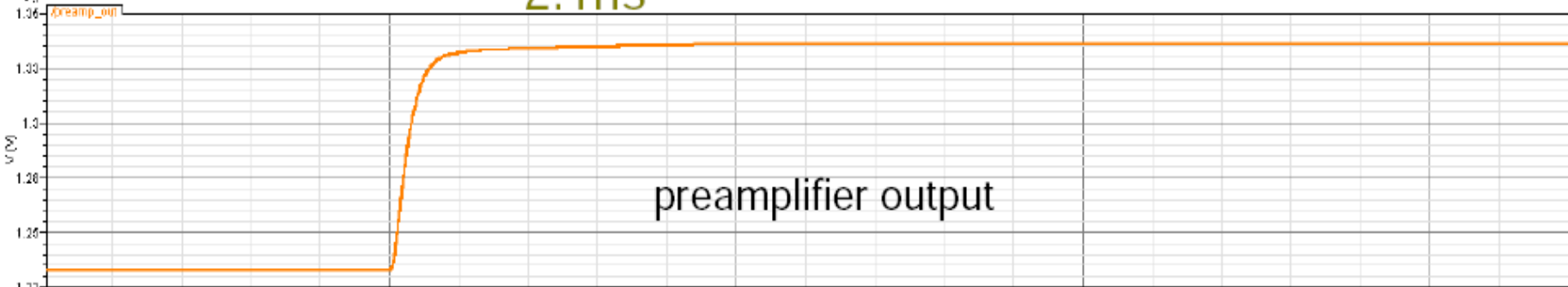
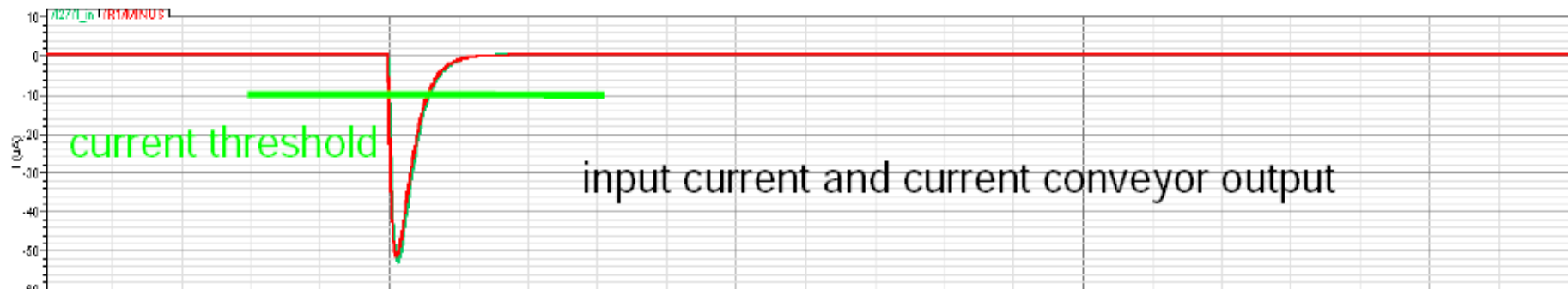
→ processing capability



current comparator

- class B output stage & 3 inverters
- Latched output , low dc offset,
- low power consumption
- ~2 ns delay with leading edge triggering
- TTL logic output
- different threshold can be set for triggering (standby current) ~50uA for calorimeter application





SUMMARY

- Analog channel designed for silicon photomultiplier
- High S/N ratio (>10 for single pixel w.r.t. 80fC charge)
- Narrow output to avoid pile up (20ns - 200ns)
- Fast trigger information (2ns delay for input current triggering)
- low power consumption : 6 mW
- dynamic range : ~120pC